

<b>Issue Classification</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10743731	KOBAYASHI, TAKEHIKO
	Examiner	Art Unit
	Nguyen, Leon-Viet Q	2611

Nguyen, Leon-Viet Q (Assistant Examiner)	7/26/07 (Date)	<i>David Payne</i> DAVID C. PAYNE SUPERVISORY PATENT EXAMINER	Total Claims Allowed:  4
<i>M. Williamson</i> (Legal Instruments Examiner)	8/19/07 (Date)	(Primary Examiner)  8/23/07 (Date)	O.G. Print Claim(s)  1